

# **High Speed IGBT3 Chip**

### Features:

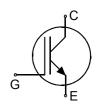
- 650V Trench & Field Stop technology
- high speed switching series third generation
- low V<sub>CE(sat)</sub>
- low EMI
- low turn-off losses
- positive temperature coefficient
- qualified according to JEDEC for target applications

# Recommended for:

discrete components and modules

#### **Applications:**

- uninterruptible power supplies
- welding converters
- converters with high switching frequency



$10001010000$ $6501/$ $400$ $4.94 \times 2.09 \text{ mm}^2$	Chip Type	$V_{\rm CE}$ $I_{\rm Cn}^{1)}$	Die Size	Package
IGC 19105QE 050V 40A 4.04 X 5.90 IIIII Sawii 011101	IGC19T65QE	650V 40A	4.84 x 3.98 mm <sup>2</sup>	sawn on foil

<sup>1)</sup> nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

### **Mechanical Parameters**

Die size		4.84 x 3.98				
Emitter pad size		See chip drawing				
Gate pad size		0.608 x 0.646				
Area total 19.26						
Thickness		70 µm				
Wafer size		200 mm				
Max. possible chips p	1412					
Passivation frontside		Photoimide				
Pad metal	netal 3200 nm AlSiCu					
Backside metal		Ni Ag –system				
Die bond		Electrically conductive epoxy glue and soft solder				
Wire bond		Al, <500µm				
Reject ink dot size	∅ 0.65mm ; max 1.2mm					
	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month				
Storage environment	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen Humidity <25%RH, Temperature 17°C – 25°C,				



### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, T <sub>vj</sub> =25 °C	V <sub>CE</sub>	650	V
DC collector current, limited by $T_{vj max}$	I <sub>C</sub>	1)	А
Pulsed collector current, $t_p$ limited by $T_{vj max}^{2}$	I <sub>c,puls</sub>	120	А
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction temperature	T <sub>vj</sub>	-40 +175	°C
Short circuit data <sup>2) 3)</sup> $V_{GE}$ = 15V, $V_{CC}$ = 400V, $T_{vj}$ = 150°C	t <sub>sc</sub>	5	μs

<sup>1)</sup> depending on thermal properties of assembly

<sup>2)</sup> not subject to production test - verified by design/characterization

<sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.

# Static Characteristics (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
	Cymbol	Conditions	min. typ.		max.	
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V , <i>I</i> <sub>C</sub> =2 mA	650			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =40A	1.48	1.95	2.32	V
Gate-Emitter threshold voltage	V <sub>GE(th)</sub>	<i>I</i> <sub>C</sub> =0.58mA , <i>V</i> <sub>GE</sub> = <i>V</i> <sub>CE</sub>	4.2	5.1	5.6	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =650V , V <sub>GE</sub> =0V			2	μA
Gate-Emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V , V <sub>GE</sub> =20V			150	nA
Integrated gate resistor	r <sub>G</sub>			none		Ω

## **Electrical Characteristics** (not subject to production test - verified by design / characterization)

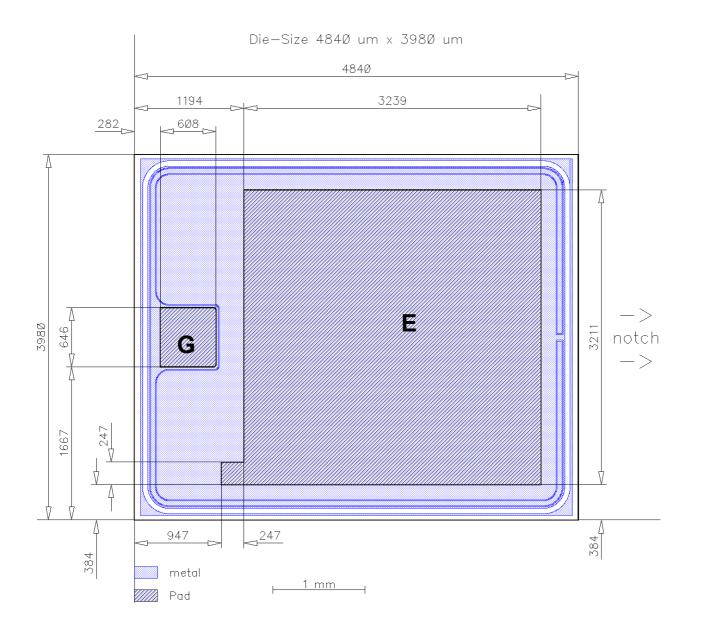
Parameter	Symbol	Conditions	Value			Unit
Faranieler			min.	typ.	max.	Unit
Collector Emitter acturation voltage	V	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =40A,		2.5		V
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	<i>T</i> <sub>vj</sub> =175 °C		2.5		V
Input capacitance	Cies	V <sub>CE</sub> =25V,		2500		
		V <sub>GE</sub> =0V, <i>f</i> =1MHz	-			pF
Reverse transfer capacitance	C <sub>res</sub>	$T_{\rm vj}$ =25 °C		75		

# **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



# **Chip Drawing**



**E =** Emitter **G** = Gate



#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

### **Revision History**

Version	Subjects (major changes since last revision)	Date

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